#### TOSHIBA Photocoupler GaAs IRed & Photo-Transistor

# **TLP630**

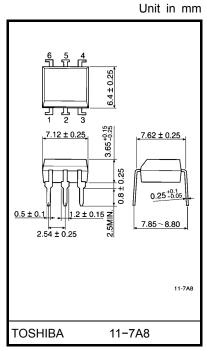
Programmable Controllers
AC / DC-Input Module
Telecommunication

The TOSHIBA TLP630 consists of a photo-transistor optically coupled to two gallium arsenide infrared emitting diode connected inverse parallel in a six lead plastic DIP package.

- Collector-emitter voltage: 55V min.
- Current transfer ratio: 50% min.

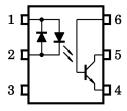
Rank GB: 100% min.

- Isolation voltage: 5000Vrms min.
- UL recognized: UL1577 file no. E67349



Weight: 0.4g

### Pin Configurations(top view)



1 : ANODE, CATHODE 2 : CATHODE, ANODE

3 : N.C.

4 : EMITTER 5 : COLLECTOR

6: BASE

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
	Forward current	I <sub>F(RMS)</sub>	60	mA	
LED	Forward current derating (Ta ≥ 39°C)	ΔI <sub>F</sub> / °C	-0.7	mA / °C	
	Peak forward current (100µs pulse,100pps)	I <sub>FPT</sub>	±1	А	
	Collector-emitter voltage	V <sub>CEO</sub>	55	V	
	Collector-base voltage	V <sub>CBO</sub>	80	V	
ctor	Emitter-collector voltage	V <sub>ECO</sub>	7	V	
Detector	Emitter-base voltage	V <sub>EBO</sub>	7	V	
	Collector current	Ic	50	mA	
	Power dissipation	PC	150	mW	
	Power dissipation derating (Ta ≥ 25°C)	ΔP <sub>C</sub> / °C	-1.5	mW / °C	
Ope	rating temperature range	T <sub>opr</sub>	-55~100	°C	
Stor	age temperature range	T <sub>stg</sub>	-55~125	°C	
Lead soldering temperature		T <sub>sol</sub>	260(10s)	°C	
Junction temperature		Tj	125	°C	
Total package power dissipation		PT	250	mW	
Total package power dissipation derating		ΔP <sub>T</sub> / °C	-2.5	mW / °C	
Isolation voltage (AC, 1 min., R.H. ≤ 60%)		BVS	5000	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Recommended Operating Conditions**

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V <sub>CC</sub>	_	5	24	V
Forward current	I <sub>F(RMS)</sub>	_	16	25	mA
Collector current	IC	_	1	10	mA
Operating temperature	T <sub>opr</sub>	-25	_	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

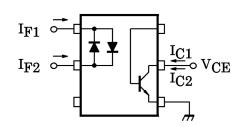
# Individual Electrical Characteristics (Ta = 25°C)

	Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10mA	1.0	1.15	1.3	V
LED	Forward current	lF	V <sub>F</sub> = 0.7V	_	2.5	10	μΑ
	Capacitance	C <sub>T</sub>	V = 0, f = 1MHz	_	60	_	pF
Detector	Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 0.5mA	55	-	-	V
	Emitter–collector breakdown voltage	V <sub>(BR)ECO</sub>	I <sub>E</sub> = 0.1mA	7	_	_	V
	Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> = 0.1mA	80	ı	ı	V
	Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 0.1mA	7	1	1	V
		Collector dark current I <sub>D</sub> (I <sub>CEO</sub> )	V <sub>CE</sub> = 24V	_	10	100	nA
	Collector dark current		V <sub>CE</sub> = 24V, Ta = 85°C	_	2	50	μΑ
	Collector dark current	I <sub>CBO</sub>	V <sub>CB</sub> = 10V	_	0.1	_	nA
	Capacitance (collector to emitter)	C <sub>CE</sub>	V = 0, f = 1MHz	_	10	_	pF

### **Coupled Electrical Characteristics (Ta = 25°C)**

Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Current transfer ratio	I <sub>C</sub> / I <sub>E</sub>	I <sub>F</sub> = ±5mA, V <sub>CE</sub> = 5V Rank GB	50	-	600	%
Current transfer fatto	10714		100	— 600	/0	
Saturated CTR	$I_{C} / I_{F(sat)}$ $I_{F} = \pm 1 \text{mA}, V_{CE} = 0.4 \text{V}$ Rank GB	_	60		%	
		Rank GB	30	-	1	/0
Base photo-current	I <sub>PB</sub>	$I_F = \pm 5$ mA, $V_{CB} = 5$ V	_	10		μA
Collector–emitter saturation voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 2.4mA, I <sub>F</sub> = ±8mA	_	ı	0.4	V
Off-state collector current	I <sub>C(off)</sub>	$V_F = \pm 0.7 V$ , $V_{CE} = 24 V$	_	1	10	μA
CTR symmetry	I <sub>C(ratio)</sub>	$I_{C}(I_{F} = -5mA) / I_{C}(I_{F} = +5mA)$ (Note 1)	0.33	1	3	_

(Note 1) 
$$I_{C(ratio)} = \frac{I_{C2}(I_F = I_{F2}, V_{CE} = 5V)}{I_{C1}(I_F = I_{F1}, V_{CE} = 5V)}$$



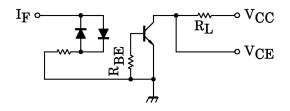
# Isolation Characteristics (Ta = 25°C)

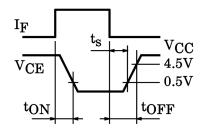
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance (input to output)	CS	V <sub>S</sub> = 0, f = 1MHz	_	0.8	_	pF
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500V, R.H. ≤ 60%	5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
		AC, 1 minute	5000	_	_	Vrms
Isolation voltage	$BV_S$	AC, 1 second, in oil	_	10000	_	VIIIIS
		DC, 1 minute, in oil	_	10000	_	Vdc

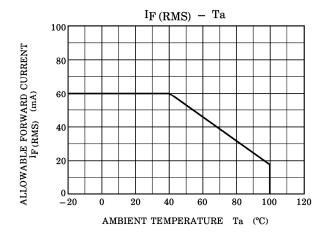
# **Switching Characteristics (Ta = 25°C)**

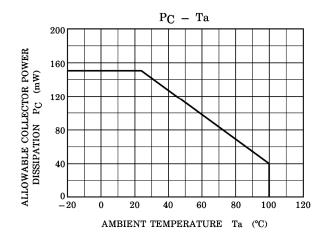
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Rise time	t <sub>r</sub>	$V_{CC}$ = 10V, $I_C$ = 2mA $R_L$ = 100 $\Omega$	_	2	_	
Fall time	t <sub>f</sub>		_	3	_	116
Turn-on time	t <sub>ON</sub>		_	3	_	μs
Turn-off time	toff		_	3	_	
Turn-on time	t <sub>ON</sub>	$R_L = 1.9 \text{ k}\Omega$ (Note 2) - $R_{BE} = \text{OPEN}$ $V_{CC} = 5 \text{ V}, I_F = \pm 16 \text{mA}$	_	2	_	
Storage time	t <sub>S</sub>		_	15	_	μs
Turn-off time	t <sub>OFF</sub>		_	25	_	
Turn-on time	t <sub>ON</sub>	$R_L = 1.9k\Omega$ (Note 2) $R_{BE} = 220k\Omega$ , $V_{CC} = 5 V$ $I_F = \pm 16mA$	_	2	_	
Storage time	t <sub>S</sub>		_	12	_	μs
Turn-off time	t <sub>OFF</sub>		_	20	_	

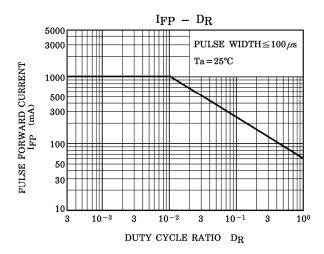
(Note 2) Switching time test circuit

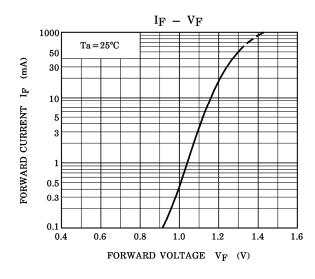


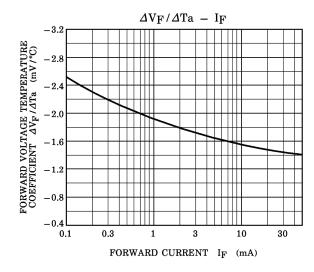


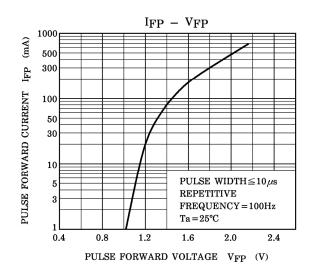


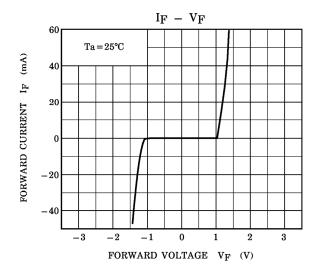


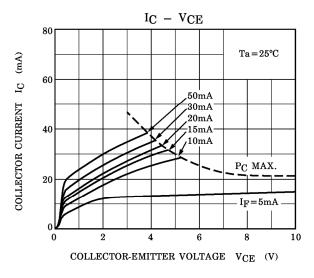


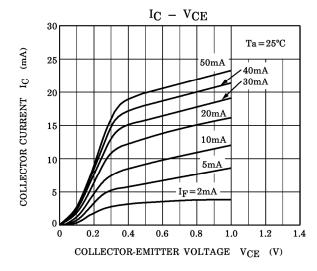


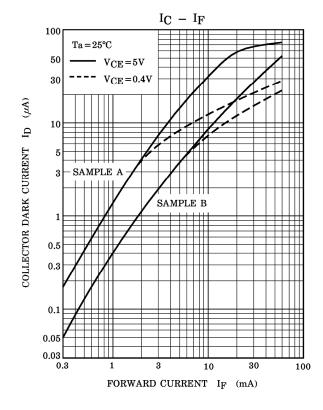


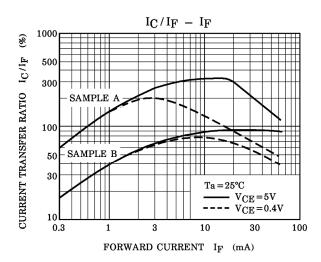


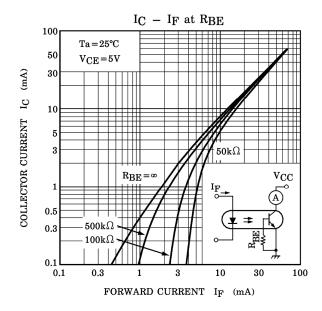


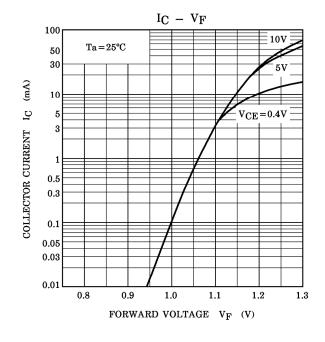


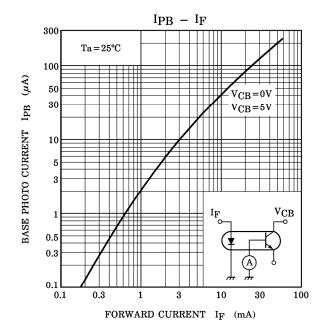


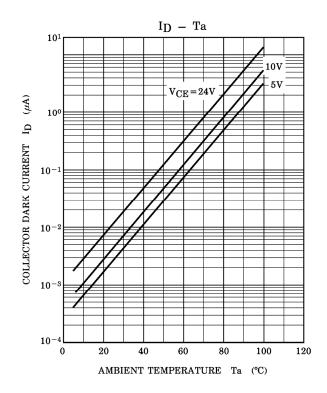


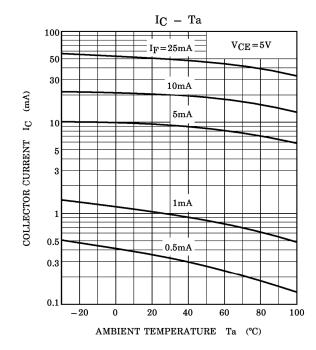


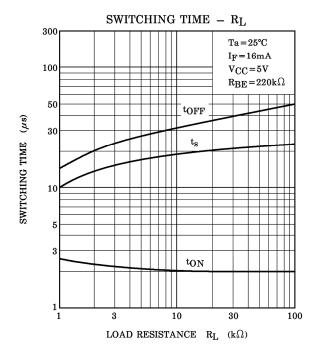


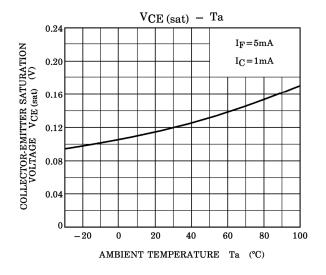


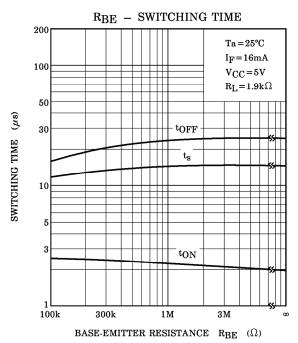


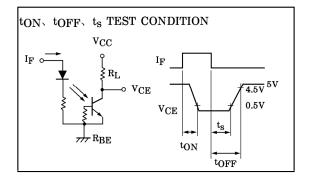












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